
Network Maintenance: Access and Testing - Special Services (SS) and SS-Like Networks

CONTENTS

[Telcordia GR-819-Documentation Information](#)

Preface	Preface-1
I. Introduction	1-1
1.1 Document History	1-1
1.2 Changes in This Document	1-1
1.3 Requirements Terminology	1-2
1.4 Graphical Conventions for Figures in FR-476	1-3
2. Overview of the Generic Test Architecture	2-1
2.1 Architecture Configurations	2-2
2.2 DLC Test Architectures	2-4
2.3 Interface Technology	2-8
2.4 Terminology Used in FR-476	2-8
3. Digital Data System (DDS) and DDS-Like Networks	3-1
3.1 DDS Overview	3-1
3.1.1 Transport Capabilities	3-1
3.1.2 Loop Signal	3-2
3.1.3 DSOA Signal	3-2
3.1.4 Control Bit and Network Control Codes	3-3
3.1.5 DS0B Signal	3-4
3.1.6 Error Correction	3-5
3.2 Secondary Channel Capability	3-6
3.3 Categories of Basic Testing Functions	3-6
3.4 Access-Related Functions	3-7
3.4.1 Supervise Digital Monitoring Access	3-7
3.4.2 Supervise Digital Splitting Access	3-8
3.4.3 Supervise Metallic Splitting Access	3-9
3.5 Circuit Configuration Functions	3-9
3.5.1 Multipoint Branch Select	3-9
3.5.2 Multipoint Branch Block	3-11
3.5.3 Operate MJU Loopback	3-12
3.5.4 Operate DS0A Loopback	3-13
3.6 Testing Functions - Digital	3-14
3.6.1 Monitor for Activity	3-14
3.6.2 Single or Simple Multiple Byte Sample	3-15
3.6.3 Activity Ratio Monitor	3-15
3.6.4 MJU Conditioning Monitor	3-15

3.6.5	Perform Office Channel Unit (OCU) Loopback Test	3-17
3.6.6	Perform HL-96NY Loopback Test	3-19
3.6.7	Perform Channel Loopback Test	3-19
3.6.8	Perform 56-kb/s Repeater Loopback Test	3-19
3.6.9	Perform Data Service Unit (DSU) Loopback Test	3-20
3.6.10	Perform Straightaway Test	3-20
3.6.10.1	Pattern Sensitive Test	3-21
3.6.10.2	Extensions for Secondary Channel Test (Optional)	3-22
3.6.11	Perform Secondary Channel MJU Test	3-23
3.7	Testing Functions - Metallic	3-27
3.7.1	Measure Foreign Voltage	3-27
3.7.2	Measure Insulation Resistance	3-27
3.7.3	Measure Loop Resistance	3-27
3.7.4	Measure Loop Capacitance	3-28
3.7.5	Measure OCU Simplex Voltage	3-28
3.7.6	Measure Insertion Loss	3-28
3.7.7	Measure Background Noise	3-29
3.7.8	Measure Impulse Noise	3-29
3.7.9	Three-Terminal Measurements	3-29
4.	High Capacity Digital Service (HCDS)	4-1
4.1	DS1 HCDS Overview	4-1
4.1.1	Transport Capabilities	4-1
4.1.2	Signal Framing and Line Codes	4-1
4.1.3	Circuit Components	4-2
4.1.4	Remote Testing	4-2
4.2	Categories of Basic Testing Functions	4-3
4.2.1	Access Supervision	4-3
4.2.1.1	Signal Presence	4-4
4.2.2	In-Service Signal Configuration	4-4
4.2.2.1	Line Rate	4-7
4.2.2.2	Digital Signal Rate Identifier	4-7
4.2.2.3	Line Code	4-7
4.2.2.4	Signal (Framing) Format	4-8
4.2.2.5	Signal (Pulse) Density	4-8
4.2.2.6	Bipolar Violations	4-8
4.2.2.7	Cyclic Redundancy Check (CRC) Violations	4-8
4.2.2.8	Parity Bit Violations	4-8
4.2.2.9	Repeated or Conventional Test Patterns	4-9
4.2.2.10	Out-of-Frame (OOF)	4-9
4.2.2.11	Change of Frame Alignment (COFA)	4-9
4.2.2.12	Timing and Clock Metrics	4-9
4.2.2.13	Alarm Conditions	4-10

4.2.2.14 Framing Bit Errors	4-10
4.2.2.15 Signal Power	4-10
4.2.2.16 Timing Jitter	4-10
4.2.2.17 Imputed Slips	4-10
4.2.2.18 ESF Data Link Message Collection	4-10
4.2.2.19 Arbitrary Frame Samples	4-11
4.2.3 Test Signal Generation	4-11
4.2.3.1 Bit Error Insertion	4-11
4.2.4 Loopback Control	4-11
4.2.5 Monitoring and Measurement of Signal	4-13
4.2.5.1 Errored-Seconds Measurements	4-14
4.2.5.2 Bit-Error Measurements	4-14
4.2.5.3 Bipolar Violation (BPV) Measurements	4-14
4.2.5.4 Change of Frame Alignment (COFA) Measurements	4-14
4.2.5.5 Measurements of Errored Extended Superframes (ESFs)	4-15
5. Testing Non-Switched and Non-Locally Switched Services in DLC Systems	5-1
5.1 Test Access Requirements for TSC/RTUs	5-1
5.2 TSC/RTUs Functional Requirements	5-1
5.2.1 Channel Testing Requirements	5-2
5.2.2 Metallic Drop Testing Requirements	5-2
5.2.3 Central Office Testing Requirements	5-2
6. Voice Frequency (VF) Special Services	6-1
Appendix A: Pattern Sensitive Testing of DDS Semites	Appendix A-1
References	References-1
Glossary	Glossary-1

LIST OF FIGURES

Figure 1-1. Conventions for FR-476	1-3
Figure 2-1. A Generic Test Architecture	2-3
Figure 2-2. Example of a Generic Test Architecture Using the DCN	2-4
Figure 2-3. Generic Test Architecture - IDLC System	2-6
Figure 2-4. Generic Test Architecture - UDLC System	2-7
Figure 3-1. DS0A Signal Format	3-3
Figure 3-2. DS0A to DSOB Conversion	3-5
Figure 3-3. Digital Monitoring Access	3-7
Figure 3-4. Digital Splitting Access	3-9
Figure 3-5. Configuring Multipoint Circuit for Testing Using Multipoint Select Function	3-11
Figure 3-6. Secondary Channel State Model	3-16
Figure 3-7. Secondary Channel MJU Test Data	3-26
Figure 4-1. Basic HCDS Circuit	4-3

LIST OF TABLES

Table 3-1. DDS Network Control Codes	3-4
Table 3-2. DDS Subrate Framing Patterns	3-5
Table 3-3. Secondary Channel Activity Inference Model	3-16